TTTC News

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PAST TTTC EVENTS

The IEEE International Test Conference (ITC 2020)
November 3–5, 2020
Washington, DC, USA
http://www.itctestweek.org/about-itc/

International Test Conference (ITC) is the world's premier venue dedicated to the electronic test of devices, boards, and systems—covering the complete cycle from design verification, design-for-test, design-for-manufacturing, silicon debug, manufacturing test, system test, diagnosis, reliability and failure analysis, and back to process and design improvement. At ITC, design, test, and yield professionals can confront challenges faced by the industry and learn how these challenges are being addressed by the combined efforts of academia, design tool and equipment suppliers, designers, and test engineers. ITC, the cornerstone of the test week event, offers a wide variety of technical activities targeted at test and design theoreticians and practitioners, including formal paper sessions, tutorials, panel sessions, case studies, invited lectures, commercial exhibits and presentations, and a host of ancillary professional meetings.

The Fifth Automotive Reliability and Test Workshop
November 6, 2020
Washington, DC, USA—Virtual Workshop
http://cas.polito.it/ART2020/

The Automotive Reliability and Test (ART) workshop focuses exclusively on test and reliability of

automotive and mission-critical electronics, including design, manufacturing, burn-in, system-level integration and in-field test, diagnosis and repair solutions, as well as architectures and methods for reliable and safe operations under different environmental conditions. With increasing system complexity, security, stringent runtime requirements for functional safety, and cost constraints of a mass market, the reliable operation of electronics in safety-critical domains is still a major challenge. The ART workshop offers a forum to present and discuss these challenges and emerging solutions among researchers and practitioners alike.

ART will take place in conjunction with the IEEE ITC and is sponsored by the Test Technology Technical Council (TTTC) of IEEE Computer Society.

The 24th Design, Automation, and Test in Europe (DATE) Conference
February 1–5, 2021
Grenoble, France
https://www.date-conference.com/

The 24th DATE conference and exhibition is the main European event bringing together designers and design automation users, researchers, and vendors, as well as specialists in the design, test, and manufacturing of electronic circuits and systems hardware and software. DATE puts a strong emphasis on both technology and systems, covering ICs/SoCs, reconfigurable hardware and embedded systems, as well as embedded software. The five-day event consists of a conference with plenary invited papers, regular papers, panels, hot-topic sessions, tutorials, workshops, special focus days, and a track for executives. The scientific conference is complemented by a commercial exhibition showing the state-of-the-art in design and test tools, methodologies, IP and design services, reconfigurable and other hardware platforms, embedded software and (industrial) design experiences from different application domains, such as automotive, wireless, telecom, and multimedia applications.

The organization of user group meetings, fringe meetings, a university booth, a PhD forum, vendor presentations, and social events offers a wide variety of extra opportunities to meet and exchange information on relevant issues for the design automation, design, and test communities. Special space will also be allocated for EU-funded projects to show their results.

UPCOMING TTTC EVENTS
The IEEE VLSI Test Symposium
April 25–28, 2021
Virtual Live Event
http://tttc-vts.org/public_html/new/2021/

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in testing, debug, and repair of microelectronic circuits and systems.

The VTS Program Committee invites original, unpublished paper submissions for VTS 2021. Proposals for the innovative practices and special sessions tracks are also invited. Paper submissions should be complete manuscripts, up to six pages (inclusive of figures, tables, and bibliography) in a standard IEEE two-column format; papers exceeding the page limit will be returned without review. Authors should clearly explain the significance of the work, highlight novel features, and describe its current status. On the title page, please include author name(s) and affiliation(s), and the mailing address, phone number, and e-mail address of the contact author. A 50-word abstract and five keywords identifying the topic area are also required.

The 2021 edition of VTS will be an online virtual interactive live event. The program includes keynotes, scientific paper presentations, short industrial application paper presentations, special sessions, and innovative practices sessions.

The 25th IEEE European Test Symposium (ETS'20)
May 24–28, 2021
Belgium—Virtual Live Event
http://ets2021.eu/

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuits and system testing, reliability, security, and validation.

In 2021, ETS will be organized virtually on-line. The symposium is organized by KU Leuven and imec that co-sponsor the event jointly with the IEEE Council on Electronic Design Automation (CEDA).

The program includes excellent keynotes, scientific papers, and highlights from industry. In addition to regular paper submissions, ETS offers a track for informal contributions dedicated to early hot ideas and relevant case studies as well as a PhD forum. A test spring school and fringe workshops will be organized in conjunction with ETS'21.

NEWSLETTER EDITOR'S INVITATION

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia 1678, Cyprus; ttheocharides@ucy.ac.cy.

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